

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	14349	((209/571) or (209/573) or (324/158.1) or (324/759) or (324/764) or (324/765) or (700/96) or (700/108) or (700/109) or (700/121)).CCLS.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/01/05 21:36
L2	376	((semiconductor chip circuit electronic) near3 (sort\$3 separat\$3 process\$3 test\$3)) same ((stor\$3 sav\$3 memory) near3 (test result flag) and ((fabricat\$3 manufactur\$3 produc\$3 process\$3) near2 (error mistake flaw deviat\$4)))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/01/05 21:37
L3	38	((semiconductor chip circuit electronic) near3 (sort\$3 separat\$3 process\$3 test\$3)) same ((stor\$3 sav\$3 memory) near3 (test result flag) and ((fabricat\$3 manufactur\$3 produc\$3 process\$3) near2 (error mistake flaw deviat\$4))).clm.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/01/05 22:36
L4	4	("7120513" "7155300").PN.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/01/05 21:39
L5	143	("20040024551" "4027246" "4032949" "4150331" "4454413" "4455495" "4510673" "4534014" "4667403" "4871963" "4954453" "4958373" "4967381" "4985988" "5003251" "5043657" "5103166" "5105362" "5110754" "5118369" "5175774" "5197650" "5217834" "5219765" "5226118" "5235550" "5253208" "5256562" "5256578" "5271796" "5289113" "5294812" "5296402" "5301143" "5326709" "5345110" "5347463" "5350715" "5352945" "5355320" "5360747" "5399531" "5420796" "5424652" "5428311" "5440240" "5440493" "5442561" "5448488" "5450326" "5467304" "5477493" "5483175" "5495417" "5504369" "5511005" "5516028" "5537325" "5538141" "5539235" "5563832" "5568408" "5570293" "5581510" "5590069" "5600171" "5603412" "5606193" "5617366" "5619469" "5625816" "5642307" "5654204" "5726074" "5764650" "5787012" "5787190" "5801067" "5801965" "5805472" "5828778" "5837558" "5844803" "5856923" "5865319" "5867505" "5889674" "5890807" "5895962" "5907492" "5915231" "5927512" "5963881" "5976899" "5991699" "5994915" "6000830" "6018686" "6049624" "6055463" "6067507" "6072574" "6075216" "6100486" "6122563" "6130442" "6138256" "6147316" "6148307" "6190972" "6194738" "6208947" "6219810" "6226394" "6259520" "6265232" "6292009" "6307171" "6350959" "6363295" "6363329" "6365421" "6365860" "6365861"). PN. OR ("6373011" "6373566" "6400840" "6424168" "6427092" "6437271" "6441897" "6504123" "6529793" "6534785" "6553276" "6588854" "6594611" "6613590" "6636068" "6654114" "6703573" "6788993" "6895538"). PN. OR ("7155300").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2008/01/05 22:03
L11	2	("5726074").PN.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/01/05 22:26
L12	87	("4027246" "4150331" "4166574" "4419747").PN. OR ("4510673").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2008/01/05 22:34

EAST Search History

L13	1295	((semiconductor chip circuit electronic) near3 (sort\$3 separat\$3 process\$3 test\$3)) same ((stor\$3 sav\$3 memory) near3 (test result flag) and (different near2 test\$3))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/01/05 22:38
L14	104	((semiconductor chip circuit electronic) near3 (sort\$3 separat\$3 process\$3 test\$3)) same ((stor\$3 sav\$3 memory) near3 (test result flag) and (different near3 (test\$3 and level)))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/01/05 22:45
L15	5	l14 and (failure near2 analysis)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/01/05 22:46